# High Voltage, High and Low Side Driver

The NCP5106 is a high voltage gate driver IC providing two outputs for direct drive of 2 N-channel power MOSFETs or IGBTs arranged in a half-bridge configuration version B or any other high-side + low-side configuration version A.

It uses the bootstrap technique to ensure a proper drive of the high-side power switch. The driver works with 2 independent inputs.

#### **Features**

- High Voltage Range: Up to 600 V
- dV/dt Immunity ±50 V/nsec
- Negative Current Injection Characterized Over the Temperature Range
- Gate Drive Supply Range from 10 V to 20 V
- High and Low Drive Outputs
- Output Source / Sink Current Capability 250 mA / 500 mA
- 3.3 V and 5 V Input Logic Compatible
- Up to V<sub>CC</sub> Swing on Input Pins
- Extended Allowable Negative Bridge Pin Voltage Swing to −10 V for Signal Propagation
- Matched Propagation Delays Between Both Channels
- Outputs in Phase with the Inputs
- Independent Logic Inputs to Accommodate All Topologies (Version A)
- Cross Conduction Protection with 100 ns Internal Fixed Dead Time (Version B)
- Under V<sub>CC</sub> LockOut (UVLO) for Both Channels
- Pin-to-Pin Compatible with Industry Standards
- These are Pb-Free Devices

## **Typical Applications**

- Half-Bridge Power Converters
- Any Complementary Drive Converters (Asymmetrical Half–Bridge, Active Clamp) (A Version Only).
- Full-Bridge Converters



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**MARKING** 

**DIAGRAMS** 







**CASE 626** 

DFN10 MN SUFFIX CASE 506DJ

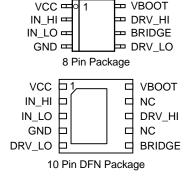


NCP5106 = Specific Device Code x = A or B version A = Assembly Location

L or WL = Wafer Lot Y or YY = Year W or WW = Work Week G or = Pb-Free Package

(Note: Microdot may be in either location)

#### PINOUT INFORMATION



#### ORDERING INFORMATION

See detailed ordering and shipping information on page 16 of this data sheet.

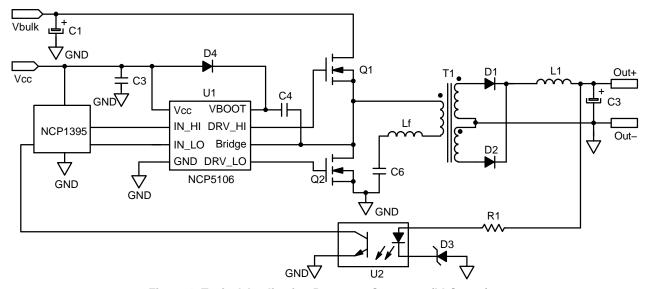


Figure 1. Typical Application Resonant Converter (LLC type)

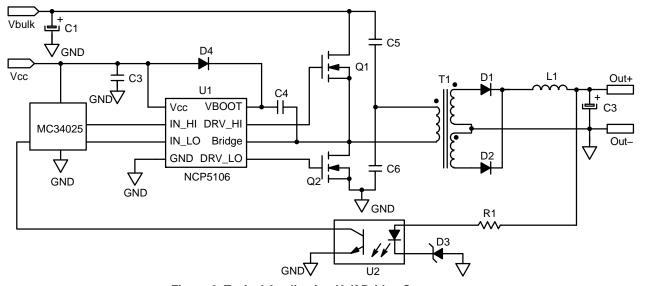


Figure 2. Typical Application Half Bridge Converter

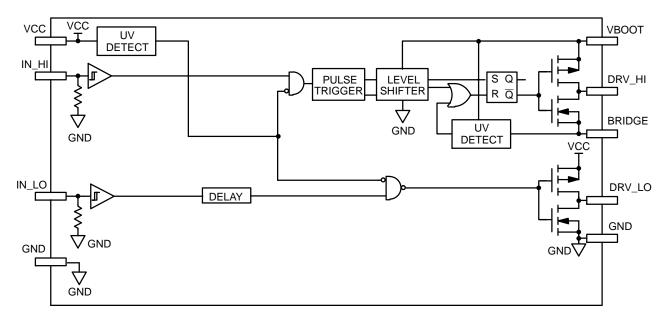


Figure 3. Detailed Block Diagram: Version A

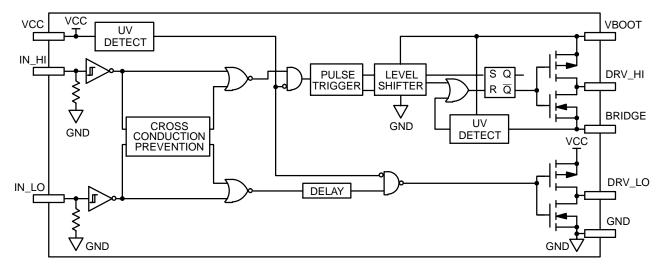


Figure 4. Detailed Block Diagram: Version B

## **PIN DESCRIPTION**

Pin Name	Description
IN_HI	Logic Input for High Side Driver Output in Phase
IN_LO	Logic Input for Low Side Driver Output in Phase
GND	Ground
DRV_LO	Low Side Gate Drive Output
V <sub>CC</sub>	Low Side and Main Power Supply
V <sub>BOOT</sub>	Bootstrap Power Supply
DRV_HI	High Side Gate Drive Output
BRIDGE	Bootstrap Return or High Side Floating Supply Return
NC	Removed for creepage distance (DFN package only)

## **MAXIMUM RATINGS**

Rating	Symbol	Value	Unit
V <sub>CC</sub>	Main power supply voltage	-0.3 to 20	V
V <sub>CC_transient</sub>	Main transient power supply voltage: IV <sub>CC_max</sub> = 5 mA during 10 ms	23	V
$V_{BRIDGE}$	VHV: High Voltage BRIDGE pin	-1 to 600	V
V <sub>BRIDGE</sub>	Allowable Negative Bridge Pin Voltage for IN_LO Signal Propagation to DRV_LO (see characterization curves for detailed results)	-10	V
$V_{BOOT-}V_{BRIDGE}$	VHV: Floating supply voltage	-0.3 to 20	V
$V_{DRV\_HI}$	VHV: High side output voltage	$V_{BRIDGE} - 0.3$ to $V_{BOOT} + 0.3$	V
V <sub>DRV_LO</sub>	Low side output voltage	-0.3 to V <sub>CC</sub> + 0.3	V
dV <sub>BRIDGE</sub> /dt	Allowable output slew rate	50	V/ns
V <sub>IN_XX</sub>	Inputs IN_HI, IN_LO	-1.0 to V <sub>CC</sub> + 0.3	V
	ESD Capability:  - HBM model (all pins except pins 6–7–8 in 8 pins package or 11–12–13 in 14 pins package)  - Machine model (all pins except pins 6–7–8 in 8 pins package or 11–12–13 in 14 pins package)	2 200	kV V
	Latch up capability per JEDEC JESD78		
$R_{\thetaJA}$	Power dissipation and Thermal characteristics PDIP–8: Thermal Resistance, Junction–to–Air SO–8: Thermal Resistance, Junction–to–Air DFN10 4x4: Thermal Resistance, Junction–to–Ambient 1 Oz Cu 50 mm² Printed Circuit Copper Clad	100 178 162	°C/W
T <sub>ST</sub>	Storage Temperature Range	-55 to +150	°C
T <sub>J_max</sub>	Maximum Operating Junction Temperature	+150	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

 $\textbf{ELECTRICAL CHARACTERISTIC} \ (V_{CC} = V_{boot} = 15 \ V, \ V_{GND} = V_{bridge}, -40 ^{\circ}\text{C} < T_{J} < 125 ^{\circ}\text{C}, \ \text{Outputs loaded with 1 nF)}$ 

Rating	1	T <sub>J</sub> –40°C to 125°C			
	Symbol	Min	Тур	Max	Units
OUTPUT SECTION			l		.1
Output high short circuit pulsed current $V_{DRV} = 0 \text{ V}$ , PW $\leq 10 \mu s$ (Note 1)	I <sub>DRVsource</sub>	_	250	_	mA
Output low short circuit pulsed current $V_{DRV} = V_{CC}$ , PW $\leq 10 \mu s$ (Note 1)	I <sub>DRVsink</sub>	_	500	_	mA
Output resistor (Typical value @ 25°C) Source	R <sub>OH</sub>	_	30	60	Ω
Output resistor (Typical value @ 25°C) Sink	R <sub>OL</sub>	_	10	20	Ω
High level output voltage, V <sub>BIAS</sub> -V <sub>DRV_XX</sub> @ I <sub>DRV_XX</sub> = 20 mA	V <sub>DRV_H</sub>	_	0.7	1.6	V
Low level output voltage V <sub>DRV_XX</sub> @ I <sub>DRV_XX</sub> = 20 mA	V <sub>DRV_L</sub>	_	0.2	0.6	V
DYNAMIC OUTPUT SECTION			I	I	, <del>1</del>
Turn-on propagation delay (Vbridge = 0 V)	t <sub>ON</sub>	_	100	170	ns
Turn-off propagation delay (Vbridge = 0 V or 50 V) (Note 2)	t <sub>OFF</sub>	_	100	170	ns
Output voltage rise time (from 10% to 90% @ V <sub>CC</sub> = 15 V) with 1 nF load	tr	_	85	160	ns
Output voltage fall time (from 90% to 10% @V <sub>CC</sub> = 15 V) with 1 nF load		_	35	75	ns
Propagation delay matching between the High side and the Low side @ 25°C (Note 3)	Δt	_	20	35	ns
Internal fixed dead time (only valid for B version) (Note 4)		65	100	190	ns
Minimum input width that changes the output		_	_	50	ns
Maximum input width that does not change the output SOIC-8, PDIP-8 DFN10	t <sub>PW2</sub>	20 15	- -	- -	ns
INPUT SECTION					
Low level input voltage threshold	V <sub>IN</sub>	-	_	0.8	V
Input pull–down resistor (V <sub>IN</sub> < 0.5 V)	R <sub>IN</sub>	_	200	_	kΩ
High level input voltage threshold	V <sub>IN</sub>	2.3	-	-	V
Logic "1" input bias current @ V <sub>IN_XX</sub> = 5 V @ 25°C	I <sub>IN+</sub>	-	5	25	μΑ
Logic "0" input bias current @ V <sub>IN_XX</sub> = 0 V @ 25°C	I <sub>IN</sub> _	_	_	2.0	μΑ
SUPPLY SECTION			•	•	•
V <sub>CC</sub> UV Start–up voltage threshold	V <sub>CC</sub> _stup	8.0	8.9	9.9	V
V <sub>CC</sub> UV Shut–down voltage threshold	V <sub>CC</sub> _shtdwn	7.3	8.2	9.1	V
Hysteresis on V <sub>CC</sub>	V <sub>CC</sub> _hyst	0.3	0.7	-	V
Vboot Start-up voltage threshold reference to bridge pin (Vboot_stup = Vboot - Vbridge)	Vboot_stup	8.0	8.9	9.9	V
Vboot UV Shut-down voltage threshold	Vboot_shtdwn	7.3	8.2	9.1	V
Hysteresis on Vboot	Vboot_hyst	0.3	0.7	-	V
Leakage current on high voltage pins to GND (VBOOT = VBRIDGE = DRV_HI = 600 V)	I <sub>HV_LEAK</sub>	-	5	40	μΑ
Consumption in active mode ( $V_{CC}$ = $V_{DO}$ , fsw = 100 kHz and 1 nF load on both driver outputs)	ICC1	-	4	5	mA
Consumption in inhibition mode (V <sub>CC</sub> = Vboot)	ICC2	_	250	400	μΑ
V <sub>CC</sub> current consumption in inhibition mode	ICC3	_	200	_	μΑ
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- Parameter guaranteed by design.
   Turn-off propagation delay @ Vbridge = 600 V is guaranteed by design.
   See characterization curve for Δt parameters variation on the full range temperature.
   Version B integrates a dead time in order to prevent any cross conduction between DRV\_HI and DRV\_LO. See timing diagram of Figure 10.

5. Timing diagram definition see: Figure 8 and Figure 9.
Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

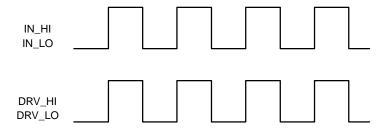


Figure 5. Input/Output Timing Diagram (A Version)

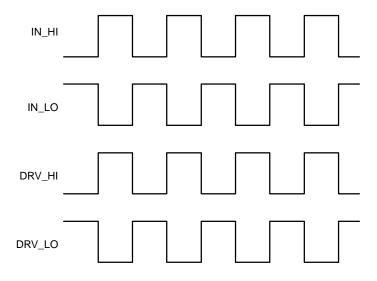


Figure 6. Input/Output Timing Diagram (B Version)

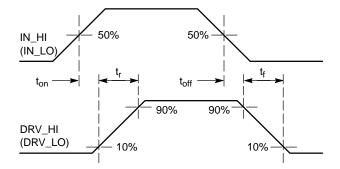


Figure 7. Propagation Delay and Rise / Fall Time Definition

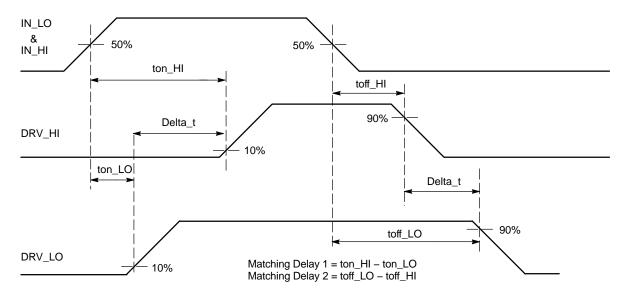


Figure 8. Matching Propagation Delay (A Version)

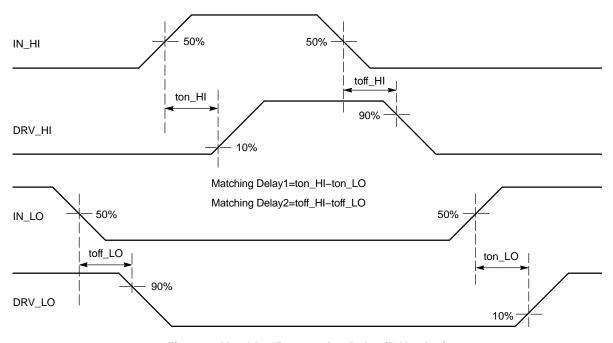


Figure 9. Matching Propagation Delay (B Version)

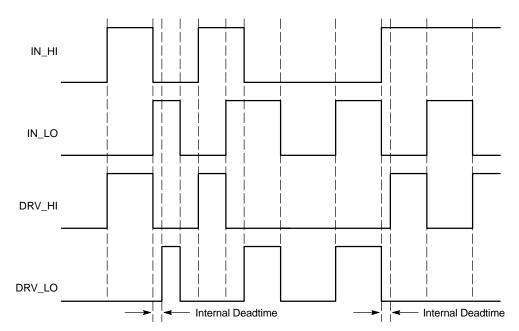
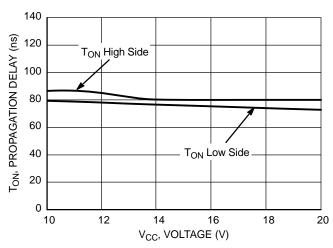


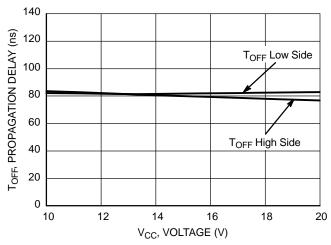
Figure 10. Input/Output Cross Conduction Output Protection Timing Diagram (B Version)



140 T<sub>ON</sub>, PROPAGATION DELAY (ns)  $T_{\mbox{ON}}$  Low Side 120 100 80 60 T<sub>ON</sub> High Side 40 20 0 -20 20 60 -40 0 40 80 100 120 TEMPERATURE (°C)

Figure 11. Turn ON Propagation Delay vs. Supply Voltage ( $V_{CC} = V_{BOOT}$ )

Figure 12. Turn ON Propagation Delay vs.
Temperature



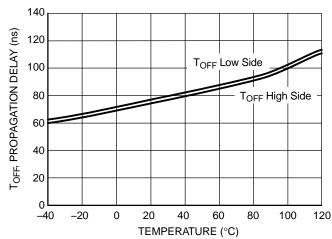
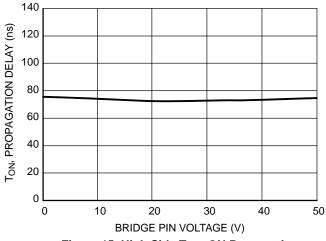


Figure 13. Turn OFF Propagation Delay vs. Supply Voltage ( $V_{CC} = V_{BOOT}$ )

Figure 14. Turn OFF Propagation Delay vs. Temperature



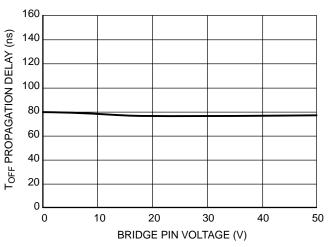


Figure 15. High Side Turn ON Propagation Delay vs. VBRIDGE Voltage

Figure 16. High Side Turn OFF Propagation Delay vs. VBRIDGE Voltage

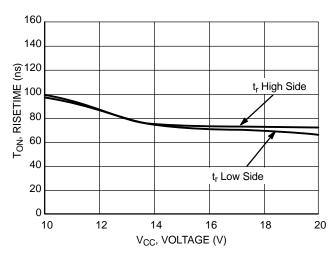


Figure 17. Turn ON Risetime vs. Supply Voltage ( $V_{CC} = V_{BOOT}$ )

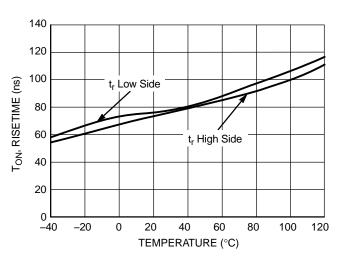


Figure 18. Turn ON Risetime vs. Temperature

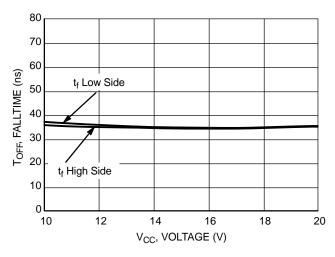


Figure 19. Turn OFF Falltime vs. Supply Voltage ( $V_{CC} = V_{BOOT}$ )

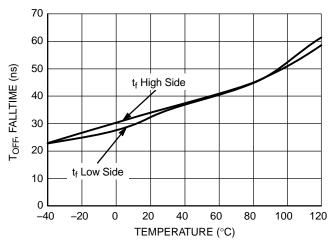


Figure 20. Turn OFF Falltime vs. Temperature

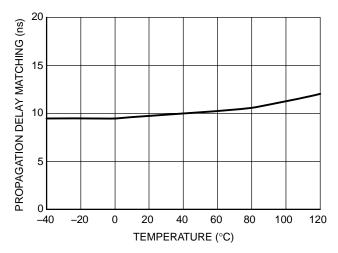


Figure 21. Propagation Delay Matching Between High Side and Low Side Driver vs. Temperature

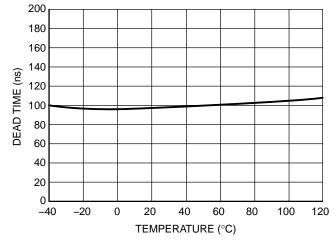


Figure 22. Dead Time vs. Temperature

## **CHARACTERIZATION CURVES**

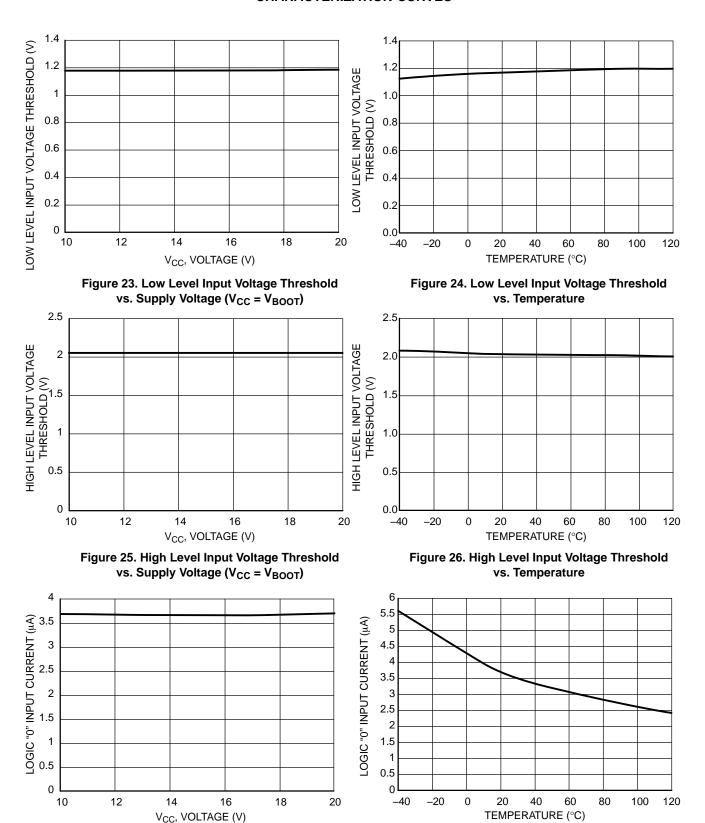


Figure 28. Logic "0" Input Current vs.

**Temperature** 

Figure 27. Logic "0" Input Current vs. Supply

Voltage ( $V_{CC} = V_{BOOT}$ )

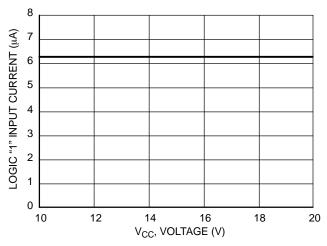


Figure 29. Logic "1" Input Current vs. Supply Voltage ( $V_{CC} = V_{BOOT}$ )

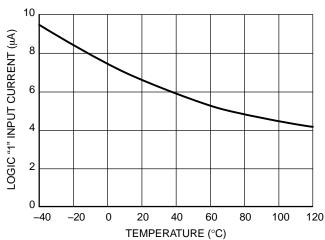


Figure 30. Logic "1" Input Current vs.
Temperature

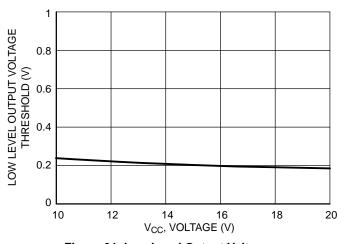


Figure 31. Low Level Output Voltage vs. Supply Voltage ( $V_{CC} = V_{BOOT}$ )

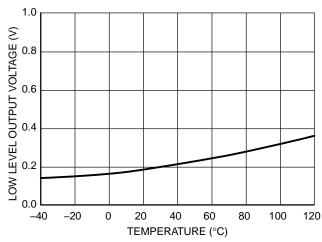


Figure 32. Low Level Output Voltage vs.
Temperature

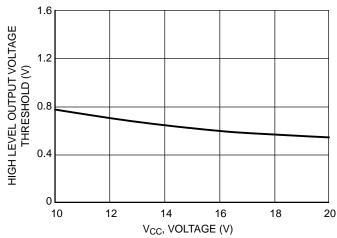


Figure 33. High Level Output Voltage vs. Supply Voltage ( $V_{CC} = V_{BOOT}$ )

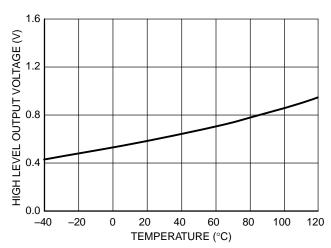


Figure 34. High Level Output Voltage vs. Temperature

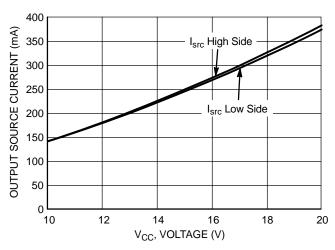


Figure 35. Output Source Current vs. Supply Voltage (V<sub>CC</sub> = V<sub>BOOT</sub>)

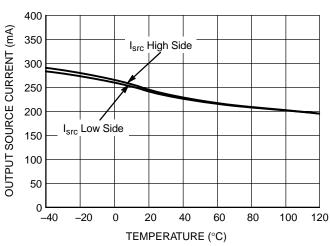


Figure 36. Output Source Current vs.
Temperature

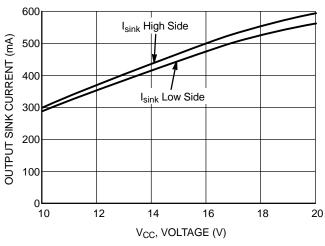


Figure 37. Output Sink Current vs. Supply Voltage (V<sub>CC</sub> = V<sub>BOOT</sub>)

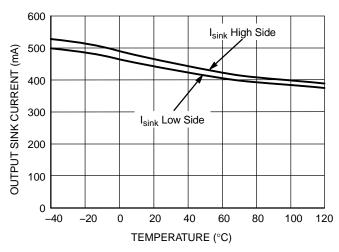


Figure 38. Output Sink Current vs.
Temperature

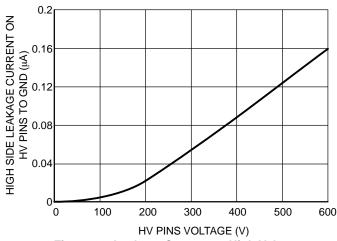


Figure 39. Leakage Current on High Voltage Pins (600 V) to Ground vs. V<sub>BRIDGE</sub> Voltage (V<sub>BRIGDE</sub> = V<sub>BOOT</sub> = V<sub>DRV</sub> HI)

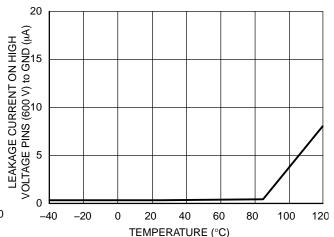


Figure 40. Leakage Current on High Voltage Pins (600 V) to Ground vs. Temperature (VBRIDGE = V<sub>BOOT</sub> = V<sub>DRV\_HI</sub> = 600 V)

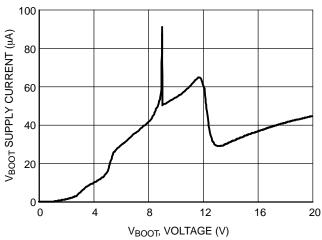


Figure 41. V<sub>BOOT</sub> Supply Current vs. Bootstrap Supply Voltage

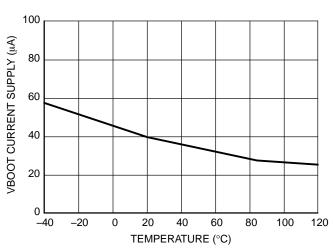


Figure 42. V<sub>BOOT</sub> Supply Current vs. Temperature

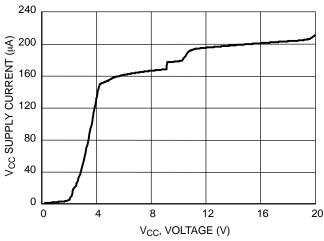


Figure 43. V<sub>CC</sub> Supply Current vs. V<sub>CC</sub> Supply Voltage

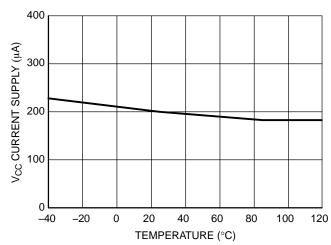


Figure 44. V<sub>CC</sub> Supply Current vs. Temperature

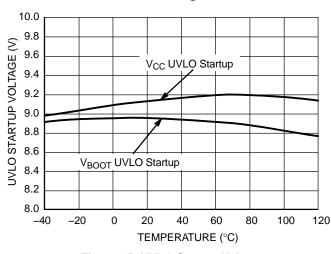


Figure 45. UVLO Startup Voltage vs. Temperature

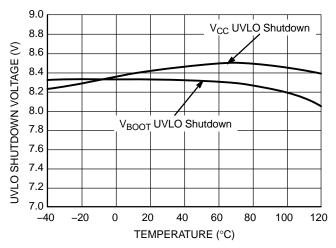


Figure 46. UVLO Shutdown Voltage vs. Temperature

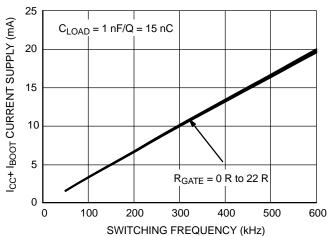


Figure 47.  $I_{CC1}$  Consumption vs. Switching Frequency with 15 nC Load on Each Driver @  $V_{CC}$  = 15 V

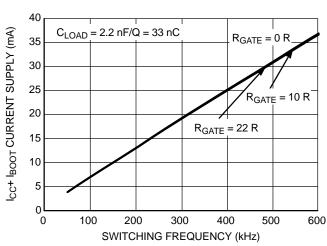


Figure 48.  $I_{CC1}$  Consumption vs. Switching Frequency with 33 nC Load on Each Driver @  $V_{CC}$  = 15 V

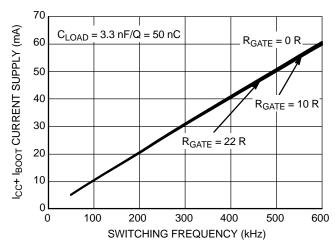


Figure 49.  $I_{CC1}$  Consumption vs. Switching Frequency with 50 nC Load on Each Driver @  $V_{CC}$  = 15 V

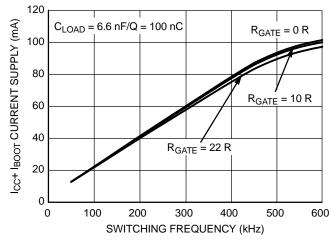


Figure 50.  $I_{CC1}$  Consumption vs. Switching Frequency with 100 nC Load on Each Driver @  $V_{CC}$  = 15 V

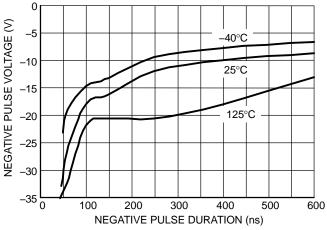


Figure 51. NCP5106A, Negative Voltage Safe Operating Area on the Bridge Pin

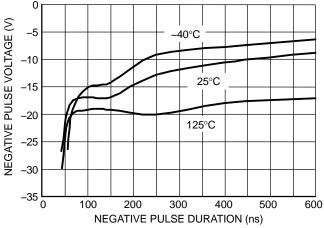


Figure 52. NCP5106B, Negative Voltage Safe Operating Area on the Bridge Pin

#### APPLICATION INFORMATION

#### **Negative Voltage Safe Operating Area**

When the driver is used in a half bridge configuration, it is possible to see negative voltage appearing on the bridge pin (pin 6) during the power MOSFETs transitions. When the high-side MOSFET is switched off, the body diode of the low-side MOSFET starts to conduct. The negative voltage applied to the bridge pin thus corresponds to the forward voltage of the body diode. However, as pcb copper tracks and wire bonding introduce stray elements (inductance and capacitor), the maximum negative voltage of the bridge pin will combine the forward voltage and the oscillations created by the parasitic elements. As any CMOS device, the deep negative voltage of a selected pin can inject carriers into the substrate, leading to an erratic behavior of the concerned component. ON Semiconductor provides characterization data of its half-bridge driver to show the maximum negative voltage the driver can safely operate with. To prevent the negative injection, it is the designer duty to verify that the amount of negative voltage pertinent to his/her application does not exceed the characterization curve we provide, including some safety margin.

In order to estimate the maximum negative voltage accepted by the driver, this parameter has been characterized over full the temperature range of the component. A test fixture has been developed in which we purposely negatively bias the bridge pin during the freewheel period of a buck converter. When the upper gate voltage shows signs of an erratic behavior, we consider the limit has been reached.

Figure 51 (or 52), illustrates the negative voltage safe operating area. Its interpretation is as follows: assume a negative 10 V pulse featuring a 100 ns width is applied on the bridge pin, the driver will work correctly over the whole die temperature range. Should the pulse swing to -20 V, keeping the same width of 100 ns, the driver will not work properly or will be damaged for temperatures below  $125^{\circ}$ C.

#### Summary:

- If the negative pulse characteristic (negative voltage level & pulse width) is above the curves the driver runs in safe operating area.
- If the negative pulse characteristic (negative voltage level & pulse width) is below one or all curves the driver will NOT run in safe operating area.

Note, each curve of the Figure 51 (or 52) represents the negative voltage and width level where the driver starts to fail at the corresponding die temperature.

If in the application the bridge pin is too close of the safe operating limit, it is possible to limit the negative voltage to the bridge pin by inserting one resistor and one diode as follows:

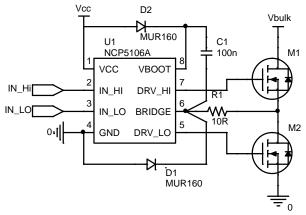


Figure 53. R1 and D1 Improves the Robustness of the Driver

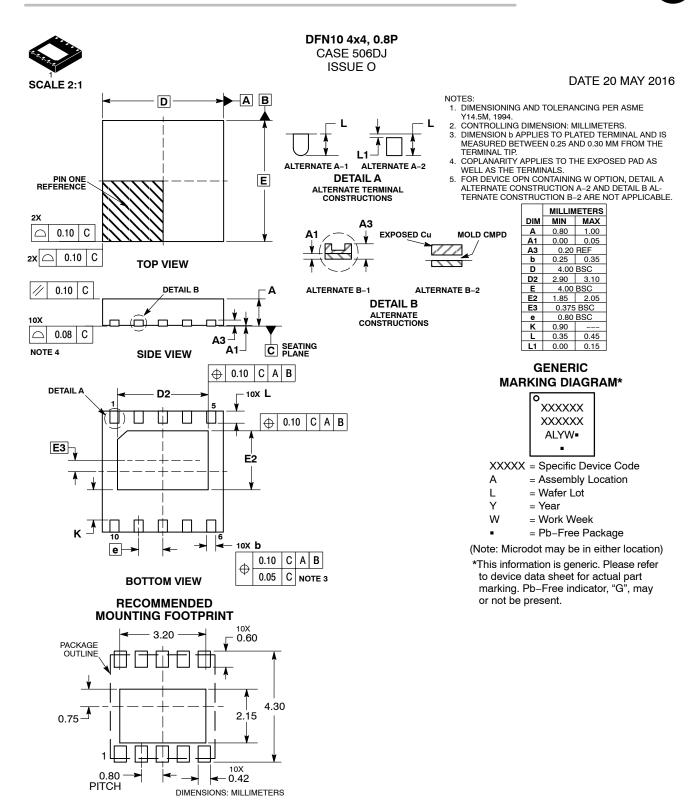
R1 and D1 should be placed as close as possible of the driver. D1 should be connected directly between the bridge pin (pin 6) and the ground pin (pin 4). By this way the negative voltage applied to the bridge pin will be limited by D1 and R1 and will prevent any wrong behavior.

#### ORDERING INFORMATION

Device	Package	Shipping <sup>†</sup>
NCP5106APG	PDIP-8 (Pb-Free)	50 Units / Rail
NCP5106ADR2G	SOIC-8 (Pb-Free)	2500 / Tape & Reel
NCP5106BPG	PDIP-8 (Pb-Free)	50 Units / Rail
NCP5106BDR2G	SOIC-8 (Pb-Free)	2500 / Tape & Reel
NCP5106AMNTWG	DFN10 (Pb-Free)	4000 / Tape & Reel
NCP5106BMNTWG	DFN10 (Pb-Free)	4000 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

## **MECHANICAL CASE OUTLINE**



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DESCRIPTION:	DFN10 4X4, 0.8P		PAGE 1 OF 1

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PDIP-8 CASE 626-05 ISSUE P

**DATE 22 APR 2015** 



**TOP VIEW** 

b2

В



NOTE 5

e/2 NOTE 3 SEATING PLANE C D1 eВ 8X b **END VIEW** |⊕|0.010 M| C| A M| B M NOTE 6 SIDE VIEW

STYLE 1: PIN 1. AC IN 2. DC + IN 3. DC - IN 4. AC IN 5. GROUND 6. OUTPUT 7. AUXILIARY 8. V<sub>CC</sub>

#### NOTES

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
- CONTROLLING DIMENSION: INCHES.
  DIMENSIONS A, A1 AND L ARE MEASURED WITH THE PACK-
- AGE SEATED IN JEDEC SEATING PLANE GAUGE GS-3.
  DIMENSIONS D, D1 AND E1 DO NOT INCLUDE MOLD FLASH OR PROTRUSIONS. MOLD FLASH OR PROTRUSIONS ARE NOT TO EXCEED 0.10 INCH.
- DIMENSION E IS MEASURED AT A POINT 0.015 BELOW DATUM PLANE H WITH THE LEADS CONSTRAINED PERPENDICULAR
- 6. DIMENSION eB IS MEASURED AT THE LEAD TIPS WITH THE
- LEADS UNCONSTRAINED.

  DATUM PLANE H IS COINCIDENT WITH THE BOTTOM OF THE LEADS, WHERE THE LEADS EXIT THE BODY.
- PACKAGE CONTOUR IS OPTIONAL (ROUNDED OR SQUARE

	INCHES		MILLIM	ETERS
DIM	MIN	MAX	MIN	MAX
Α		0.210		5.33
A1	0.015		0.38	
A2	0.115	0.195	2.92	4.95
b	0.014	0.022	0.35	0.56
b2	0.060 TYP		1.52	TYP
С	0.008	0.014	0.20	0.36
D	0.355	0.400	9.02	10.16
D1	0.005		0.13	
E	0.300	0.325	7.62	8.26
E1	0.240	0.280	6.10	7.11
е	0.100 BSC		2.54	BSC
eВ		0.430		10.92
L	0.115	0.150	2.92	3.81
М		10°		10°

## **GENERIC MARKING DIAGRAM\***



XXXX = Specific Device Code = Assembly Location

WL = Wafer Lot YY = Year WW = Work Week = Pb-Free Package

\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot " ■", may or may not be present.

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SOIC-8 NB CASE 751-07 **ISSUE AK** 

**DATE 16 FEB 2011** 



- NOTES:
  1. DIMENSIONING AND TOLERANCING PER
- ANSI Y14.5M, 1982.
  CONTROLLING DIMENSION: MILLIMETER.
- DIMENSION A AND B DO NOT INCLUDE MOLD PROTRUSION.
- MAXIMUM MOLD PROTRUSION 0.15 (0.006) PER SIDE
- DIMENSION D DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.127 (0.005) TOTAL IN EXCESS OF THE D DIMENSION AT MAXIMUM MATERIAL CONDITION.
- 751-01 THRU 751-06 ARE OBSOLETE. NEW STANDARD IS 751-07.

	MILLIMETERS		INC	HES
DIM	MIN	MAX	MIN	MAX
Α	4.80	5.00	0.189	0.197
В	3.80	4.00	0.150	0.157
С	1.35	1.75	0.053	0.069
D	0.33	0.51	0.013	0.020
G	1.27 BSC		0.050 BSC	
Н	0.10	0.25	0.004	0.010
J	0.19	0.25	0.007	0.010
K	0.40	1.27	0.016	0.050
М	0 °	8 °	0 °	8 °
N	0.25	0.50	0.010	0.020
S	5.80	6.20	0.228	0.244

## **SOLDERING FOOTPRINT\***



<sup>\*</sup>For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

## **GENERIC MARKING DIAGRAM\***



XXXXX = Specific Device Code = Assembly Location

= Wafer Lot = Year = Work Week

= Pb-Free Package



XXXXXX = Specific Device Code = Assembly Location Α

= Year ww = Work Week

= Pb-Free Package

\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "•", may or may not be present. Some products may not follow the Generic Marking.

#### **STYLES ON PAGE 2**

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## DATE 16 FEB 2011

STYLE 3: PIN 1. DRAIN, PIE #1 CTOR, #1 CTOR, #2 CTOR, #1 CTOR, #2 CTOR, #2 CTOR, #2 CTOR, #2 CTOR, #1	2. ANODE 3. ANODE 4. ANODE 5. ANODE 6. ANODE 7. ANODE 8. COMMON CATHODE  STYLE 8: PIN 1. COLLECTOR, DIE #1 2. BASE, #1 3. BASE, #2 4. COLLECTOR, #2 5. COLLECTOR, #2 6. EMITTER, #1 Vd  STYLE 12: PIN 1. SOURCE 2. SOURCE 3. SOURCE 3. SOURCE 4. GATE 5. DRAIN 6. DRAIN 7. DRAIN 8. DRAIN 8. TYLE 16: PIN 1. EMITTER, DIE #1 2. BASE, DIE #1 3. EMITTER, DIE #1
E PIN 1. INPUT 2. EXTERNAL BY 3. THIRD STAGE 4. GROUND E 5. DRAIN 6. GATE 3 7. SECOND STAGE 8. FIRST STAGE STYLE 11: ID PIN 1. SOURCE 1 2. GATE 1 T 3. SOURCE 2 ID 4. GATE 2 ID 5. DRAIN 2 6. DRAIN 2 7. DRAIN 1 ID 8. DRAIN 1 ID	PIN 1. COLLECTOR, DIE #1 2. BASE, #1 3. BASE, #2 4. COLLECTOR, #2 5. COLLECTOR, #2 6. EMITTER, #2 7. EMITTER, #1 Vd 8. COLLECTOR, #1  STYLE 12: PIN 1. SOURCE 2. SOURCE 3. SOURCE 4. GATE 5. DRAIN 6. DRAIN 7. DRAIN 8. DRAIN 8. TYLE 16: PIN 1. EMITTER, DIE #1 2. BASE, DIE #1 3. EMITTER, DIE #2
ID PIN 1. SOURCE 1 2. GATE 1 T 3. SOURCE 2 ID 4. GATE 2 ID 5. DRAIN 2 6. DRAIN 2 7. DRAIN 1 ID 8. DRAIN 1 STYLE 15: RCE PIN 1. ANODE 1 E 2. ANODE 1 RCE 3. ANODE 1	PIN 1. SOURCE 2. SOURCE 3. SOURCE 4. GATE 5. DRAIN 6. DRAIN 7. DRAIN 8. DRAIN STYLE 16: PIN 1. EMITTER, DIE #1 2. BASE, DIE #1 3. EMITTER, DIE #2
STYLE 15:  RCE PIN 1. ANODE 1 E 2. ANODE 1 RCE 3. ANODE 1	PIN 1. EMITTER, DIE #1 2. BASE, DIE #1 3. EMITTER, DIE #2
N 7. CATHODE, CON N 8. CATHODE, CON	MMON         5. COLLECTOR, DIE #2           MMON         6. COLLECTOR, DIE #2           MMON         7. COLLECTOR, DIE #1           MMON         8. COLLECTOR, DIE #1
STYLE 19: PIN 1. SOURCE 1 E 2. GATE 1 E 3. SOURCE 2 4. GATE 2 5. DRAIN 2 6. MIRROR 2 DE 7. DRAIN 1 DE 8. MIRROR 1	STYLE 20: PIN 1. SOURCE (N) 2. GATE (N) 3. SOURCE (P) 4. GATE (P) 5. DRAIN 6. DRAIN 7. DRAIN 8. DRAIN
STYLE 23: E1 PIN 1. LINE 1 IN DN CATHODE/VCC 2. COMMON ANC DN CATHODE/VCC 3. COMMON ANC E3 4. LINE 2 IN DN ANODE/GND 5. LINE 2 OUT E4 6. COMMON ANC E5 7. COMMON ANC DN ANODE/GND 8. LINE 1 OUT	ODE/GND 2. EMITTER ODE/GND 3. COLLECTOR/ANODE
STYLE 27: PIN 1. ILIMIT 2. OVLO 3. UVLO 4. INPUT+ 5. SOURCE 6. SOURCE 6. SOURCE 7. SOURCE 8. DRAIN	STYLE 28: PIN 1. SW_TO_GND 2. DASIC_OFF 3. DASIC_SW_DET 4. GND 5. V MON 6. VBULK 7. VBULK 8. VIN
1 1	
;	STYLE 27: PIN 1. ILIMIT 2. OVLO 3. UVLO 4. INPUT+ E 5. SOURCE E 6. SOURCE E 7. SOURCE 8. DRAIN

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